



Product Change Notification - KSRA-12PACO579

Date:

14 Sep 2018

Product Category:

8-bit Microcontrollers

Affected CPNs:**Notification subject:**

CCB 3546 Initial Notice: Qualification of MTAI as an additional final test site for selected Atmel ATTINY products available in 14L SOIC package.

Notification text:**PCN Status:**

Initial notification

PCN Type:

Manufacturing Change

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:

Qualification of MTAI as an additional final test site for selected Atmel ATTINY products available in 14L SOIC package.

Pre Change:

Tested at LPI final test site.

Post Change:

Tested at LPI final test site or tested at MTAI final test site.

Pre and Post Change Summary:

| | Pre Change | Post Change | |
|-----------------|---|---|---|
| Final Test Site | Lingsen Precision Industries, LTD. (LPI) | Lingsen Precision Industries, LTD. (LPI) | Microchip Technology Thailand (HQ) (MTAI) |

Impacts to Data Sheet:

None

Change Impact:

None

Reason for Change:

To improve manufacturability by qualifying MTAI as an additional final test site.

Change Implementation Status:

In Progress

Estimated Qualification Completion Date:

December 2018

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.



Time Table Summary:

| | September 2018 | | | | | --> | December 2018 | | | | |
|--------------------------|----------------|----|----|----|----|-----|---------------|----|----|----|----|
| Workweek | 35 | 36 | 37 | 38 | 39 | | 48 | 49 | 50 | 51 | 52 |
| Initial PCN Issue Date | | | | X | | | | | | | |
| Qual Report Availability | | | | | | | | | | | X |
| Final PCN Issue Date | | | | | | | | | | | X |

Method to Identify Change:

Traceability code

Qualification Plan:

Please open the attachments included with this PCN labeled as PCN_#_Qual Plan.

Revision History:

September 14, 2018: Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):

[PCN_KSRA-12PACO579_Qual_Plan.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to change your product/process change notification (PCN) profile please log on to our website at <http://www.microchip.com/PCN> sign into myMICROCHIP to open the myMICROCHIP home page, then select a profile option from the left navigation bar.

To opt out of future offer or information emails (other than product change notification emails), click here to go to [microchipDIRECT](#) and login, then click on the "My account" link, click on "Update profile" and un-check the box that states "Future offers or information about Microchip's products or services."

Affected Catalog Part Numbers (CPN)

ATTINY20-SSU
ATTINY20-SSUR
ATTINY20-SSURB47
ATTINY441-SSU
ATTINY441-SSUR
ATTINY841-SSU
ATTINY841-SSUR
ATTiny24A-SSF
ATTiny24A-SSFR
ATTiny44A-SSF
ATTiny44A-SSFR
ATTiny84A-SSU
ATTiny84A-SSUR



MICROCHIP

QUALIFICATION PLAN SUMMARY

PCN #: KSRA-12PACO579

Date

September 07, 2018

Qualification of MTAI as an additional final test site for selected Atmel ATTINY products available in 14L SOIC package.

Purpose: Qualification of MTAI as an additional final test site for selected Atmel ATTINY products available in 14L SOIC package.

CCB No.: 3546

| Test / Evaluation | Test Conditions / Parameters |
|---|---|
| Datalog / Bin Comparison | <ul style="list-style-type: none"> • Compare test numbers, test names, test limit, test sequence, bin assignments & pass/fail results. • Accept if all match or justify the differences |
| Site by site verification | <ul style="list-style-type: none"> • Verifies the channel map has the correct site assignments and tester/handler communication work correctly |
| Correlation lot report | <ul style="list-style-type: none"> • Yield at each step and reject analysis between systems. 5K units are tested for each program conversion we perform. • Accept on yield match within 1% |
| Unit to unit parametric correlation | <ul style="list-style-type: none"> • A full assembly strip characterized on both systems and graphed vs each other & the data sheet limits |
| Test stability | <ul style="list-style-type: none"> • 50 loop test performed with no datalog delays • Accept on 0 fails |
| Parametric test stability verification | <ul style="list-style-type: none"> • Use Real Time Statistics software to create CPK report of all parametric tests • Accept on Cpk > 1.67 or explainable |